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Substitute for form 1449A/PTO							Application Nur		10/785,254		
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT						_ ,	First Named Inv	entor:	Linyong Pang		
(Use as many sheets as necessary)							Examiner: Sun	J. Lin	GROUP: 2825		
Sheet	Sheet I		of 1			Attorney Dock	et Number NTI-849				
U.S. PATENT DOCUMENTS											
Examiner Initials*			<u>Document Number</u> Number - Kind Code ² (/tmovn)			v			Patentee or Cited Documen	Pages, Columns, Lines t Where Relevant Passages or Figures Appear	
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EXAMINER SIGNATURE: James Sun fins DATE CONSIDERED: 11-07-05											

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